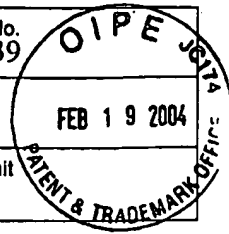


Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-126004	Application No. 10/647,539
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki et al.	
		Filing Date August 26, 2003	Group Art Unit 2814



U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
LP	AA	5,529,937	06/25/1996	Zhang et al.			07/20/1994
	AB	5,643,826	07/01/1997	Ohtani et al.			10/25/1994
	AC	5,696,003	12/09/1997	Makita et al.			12/16/1994
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Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
LP	AL	0 651 431 A2	05/03/1995	EUROPE			IN ENGLISH	
	AM	1995-0004453	02/18/1995	KOREA			ABS	
	AN	1995-0012580	05/16/1995	KOREA			ABS	
	AO	1995-0021777	07/26/1995	KOREA			ABS	
	AP	1997-0063763	09/12/1997	KOREA			ABS	

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature <i>Long Pham</i>	Date Considered <i>4/18/04</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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	AB	5,042,918	08/1991	Suzuki			
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							Yes	No
LP	AW	06-232059	08/19/1994	JAPAN			Yes	
LP	AX	06-244103	09/02/1994	JAPAN			Abst.	

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							Yes	No
LP	AY	07-321339	12/08/1995	JAPAN			Abst.	
↓	BA	08-255916	10/1/1996	JAPAN			Abst.	

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↓	BE	Wolf, S., et al. "Silicon Processing for the VLSI Era Volume 1: Process Technology", Lattice Press, Sunset Beach, CA, pp. 61-65, 335.
↓	BF	Wolf, S., "Silicon Processing for the VLSI Era Volume 3: The Submicron MOSFET", Sunset Beach, CA, p. 648.

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Substitute Form PTO-1449

U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
07977-126004Application No.
10/647,539Information Disclosure Statement
by Applicant

(Use several sheets if necessary)

Applicant
Shunpei Yamazaki et al.Filing Date
August 26, 2003

Group Art Unit

(37 CFR 1.98(b))

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	AK						

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LP	AL	08-255916	10/01/1996	JAPAN			Full	
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